

Search Notes

Application/Control No.

10/754,321

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DuyVu n. Deo

Applicant(s)/Patent under
Reexamination

MAK ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: key words, class/sub (438/14-17, 257/48; 156/345.1; 250/307-310)	12/27/2005	